

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
36179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**  
(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun et al.

Filing Date  
April 27, 2006

Confirmation No.  
3634

**U.S. PATENT DOCUMENTS**

*Exam. Init.		Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
		4	5	3	3	2	4	7	August 6, 1985	Epworth eeeeeeee			
		6	7	4	1	3	5	5	May 25, 2004	Drabarek eeeeeeee			
2005	0	0	7	5	5	4	7		April 7, 2005	Wang eeeeeeee			
2005	0	0	8	3	5	3	4		April 21, 2005	Riza et al. eeeeeeee			
		3	9	7	3	2	1	9	August 3, 1976	Tang et al.			
		3	9	8	3	5	0	7	September 28, 1976	Tang et al.			
2006	0	1	0	3	8	5	0		May 18, 2006	Alphonse et al. eeeeeeeeee			
		4	8	9	2	4	0	6	January 9, 1990	Waters eeeeeeeeee			
		5	7	1	6	3	2	4	February 10, 1998	Toida φ			
		6	4	5	9	4	8	7	October 1, 2002	Chen et al.φ			
2002	0	0	9	3	6	6	2		July 18, 2002	Chen et al. φ			
		6	3	5	9	6	9	2	March 19, 2002	Groot φφφ			
		6	9	0	3	8	2	0	June 7, 2005	Wang φφφφ			
2006	0	2	4	4	9	7	3		November 2, 2006	Yun et al. φφφφφφ			
		5	2	2	8	0	0	1	July 13, 1993	Birge et al. φφφφφφ			
		6	6	8	7	0	3	6	February 3, 2004	Riza φφφφφφ			
		4	4	2	8	6	4	3	January 31, 1984	Kay φφφφφφ			
		4	9	6	5	5	9	9	October 23, 1990	Roddy et al. φφφφφφ			

Examiner

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		4	3	0	3	3	0	0	December 1, 1981	Pressiat et al.			
		6	8	3	9	4	9	6	January 4, 2005	Mills et al.			
2004	0	1	3	3	1	9	1	July 8, 2004	Momiuchi et al. ΦΦΦΦΦΦΦ				
	5	8	4	0	0	7	5	November 24, 1998	Mueller et al. ΦΦΦΦΦΦΦ				
2003	0	2	1	6	7	1	9	November 20, 2003	Debenedictics et al. ΦΦΦΦΦΦΦ				
2006	0	1	5	5	1	9	3	July 13, 2006	Leonardi et al. ΦΦΦΦΦΦΦ				
2003	0	1	9	9	7	6	9	October 23, 2003	Podoleanu et al. ΦΦΦΦΦΦΦΦΦ				
2004	0	2	1	2	8	0	8	October 28, 2004	Okawa et al. ΦΦΦΦΦΦΦΦΦ				

**FOREIGN PATENT DOCUMENT**

		Document No.							Date	Country	Class	SubClass	Translator Yes No
		9	6	2	8	2	1	2	September 19, 1996	WIPO ΦΦΦΦΦΦΦΦΦΦΦΦ			
		0	9	3	3	0	9	6	August 4, 1999	European ΦΦΦΦΦΦΦΦΦΦΦΦ			
		4	1	0	5	2	2	1	September 12, 1991	Germany			
		0	1	0	8	5	7	9	February 8, 2001	WIPO ΦΦΦΦΦΦΦ			
		9	9	0	5	4	8	7	February 4, 1999	WIPO ΦΦΦΦΦΦΦΦΦ			
200	5	0	8	2	2	2	5	September 9, 2005	WIPO ΦΦΦΦΦΦΦΦΦΦΦ				
200	4	0	3	4	8	6	9	April 29, 2004	WIPO ΦΦΦΦΦΦΦΦΦΦΦ				

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	0	3	0	5	2	4	7	8	June 26, 2003	WIPO ΦΦΦΦΦΦΦΦΦΦ				
	200	7	0	3	8	7	8	7	April 5, 2007	WIPO ΦΦΦΦΦΦΦΦΦΦ				

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Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/435,228

Reference cited in Office Action dated January 10, 2008 for U.S. Patent Application No. 11/410,937

Reference cited in Office Action dated January 11, 2008 for U.S. Patent Application No. 11/445,990

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References cited in International Search Report PCT/US2007/061481 dated March 17, 2008

References cited in International Search Report PCT/US2007/078254 dated March 28, 2008

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		Schmitt M. Joseph et al. "OCT elastography: imaging microscopic deformation and strain of tissue", Optics Express, Vol. 3, No. 6, September 14, 1998, pages 199-211 <del>eeeeeeeeee</del>
		M. Gualini Muddassir et al., "Recent Advancements of Optical Interferometry Applied to Medicine", IEEE Transactions on Medical Imaging, Vol. 23, No. 2, February 2004, pages 205-212
		Maurice L. Roch et al. "Noninvasive Vascular Elastography: Theoretical Framework", IEEE Transactions on Medical Imaging, Vol. 23, No. 2, February 2004, pages 164-180 <del>eeeeeeeeee</del>
		Kirkpatrick J. Sean et al. "Optical Assessment of Tissue Mechanical Properties", Proceedings of the SPIE - The International Society for Optical Engineering SPIE - Vol. 4001, 2000, pages 92-101 <del>eeeeeeeeee</del>
		Lisauskas B. Jennifer et al., "Investigation of Plaque Biomechanics from Intravascular Ultrasound Images using Finite Element Modeling", Proceedings of the 19 <sup>th</sup> International Conference - IEEE October 30 – November 2, 1997, pages 887-888 <del>eeeeeeeeee</del>
		Parker K. J. et al., "Techniques for Elastic Imaging: A Review", IEEE Engineering in Medicine and Biology, November/December 1996, pages 52-59 <del>eeeeeeeeee</del>
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		Dubois Arnaud et al., "Ultrahigh-resolution OCT using white-light interference microscopy", Proceedings of SPIE, 2003, Vol. 4956, pages 14-21 <del>phi</del>
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		Copy of Office Action dated February 4, 2008 for U.S. Patent Application No. 10/861,179
		Copy of PCT International Search Report and Written Opinion for Application No. PCT/US2007/061463 dated January 23, 2008
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Examiner /Michael A. Lyons/ Date Considered 08/01/2008

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